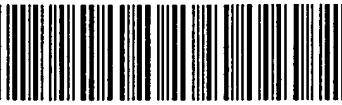
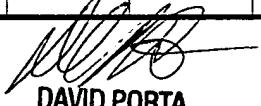


Issue Classification				Application/Control No.		Applicant(s)/Patent under Reexamination	
				10/633,595		OIKAWA ET AL.	
				Examiner		Art Unit	
				Patrick J. Lee		2878	

ISSUE CLASSIFICATION

ORIGINAL				CROSS REFERENCE(S)									
CLASS		SUBCLASS		CLASS		SUBCLASS (ONE SUBCLASS PER BLOCK)							
250		221		250		222.1	234						
INTERNATIONAL CLASSIFICATION				340		555							
G	0	6	M	7/00									
H	0	1	J	40/14									
				/									
				/									
				/									
Patrick J. Lee (Assistant Examiner) (Date) <i>6/15/05</i>				 DAVID PORTA SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2800 (Primary Examiner) <i>6/23/05</i>								Total Claims Allowed: 16	
<i>Christine Moore</i> (Legal Instruments Examiner) (Date)												O.G. Print Claim(s) 1	O.G. Print Fig. 1

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R. 1.47	
Final	Original	Final	Original	Final	Original	Final	Original
1	1	31	61	91	121	151	181
2	2	32	62	92	122	152	182
11	3	33	63	93	123	153	183
12	4	34	64	94	124	154	184
3	5	35	65	95	125	155	185
13	6	36	66	96	126	156	186
14	7	37	67	97	127	157	187
15	8	38	68	98	128	158	188
16	9	39	69	99	129	159	189
4	10	40	70	100	130	160	190
5	11	41	71	101	131	161	191
6	12	42	72	102	132	162	192
7	13	43	73	103	133	163	193
8	14	44	74	104	134	164	194
9	15	45	75	105	135	165	195
10	16	46	76	106	136	166	196
	17	47	77	107	137	167	197
	18	48	78	108	138	168	198
	19	49	79	109	139	169	199
	20	50	80	110	140	170	200
	21	51	81	111	141	171	201
	22	52	82	112	142	172	202
	23	53	83	113	143	173	203
	24	54	84	114	144	174	204
	25	55	85	115	145	175	205
	26	56	86	116	146	176	206
	27	57	87	117	147	177	207
	28	58	88	118	148	178	208
	29	59	89	119	149	179	209
	30	60	90	120	150	180	210